

EPC2007C – Enhancement Mode Power Transistor

 V_{DS} , 100 V $R_{DS(on)}$, 30 mΩ I_D , 6 A

Halogen-Free

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings

PARAMETER		VALUE	UNIT
V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
I_D	Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 62^\circ\text{C/W}$)	6	A
	Pulsed (25°C , $T_{PULSE} = 300 \mu\text{s}$)	40	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature	-40 to 150	

Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	3.6	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	9.3	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	80	

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 75 \mu\text{A}$	100			V
I_{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$, $V_{DS} = 80 \text{ V}$		20	60	μA
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.25	2	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		20	60	μA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1.2 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$, $I_D = 6 \text{ A}$		24	30	mΩ
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$, $V_{GS} = 0 \text{ V}$		2.1		V

All measurements were done with substrate connected to source.



EPC2007C eGaN® FETs are supplied only in passivated die form with solder bumps

Applications

- High Speed DC-DC conversion
- Class-D Audio
- Wireless Power Transfer
- Lidar

Benefits

- Ultra High Efficiency
- Zero Q_{RR}
- Ultra Low Q_G
- Ultra Small Footprint



Dynamic Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C_{ISS}	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		170	220	pF
C_{RSS}	Reverse Transfer Capacitance			1.9	2.7	
C_{OSS}	Output Capacitance			110	165	
R_G	Gate Resistance			0.4		Ω
Q_G	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 6\text{ A}$		1.6	2.2	nC
Q_{GS}	Gate-to-Source Charge	$V_{DS} = 50\text{ V}, I_D = 6\text{ A}$		0.6		
Q_{GD}	Gate-to-Drain Charge			0.3	0.6	
$Q_{G(TH)}$	Gate Charge at Threshold			0.4		
Q_{OSS}	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		8.3	12.5	
Q_{RR}	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS} .

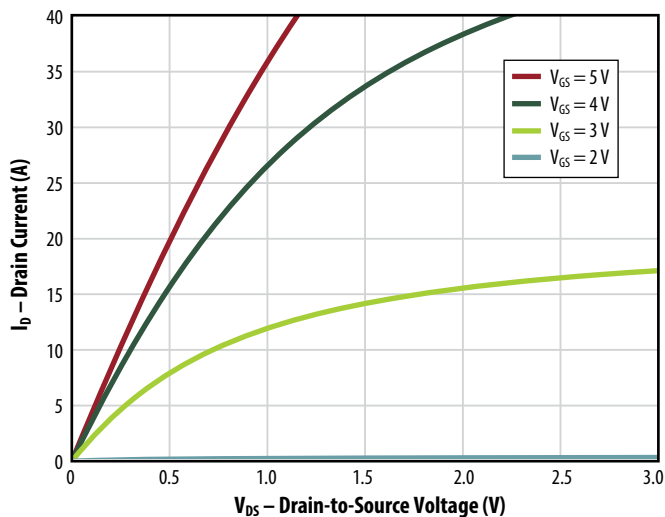
Figure 1: Typical Output Characteristics at 25°C 

Figure 2: Transfer Characteristics

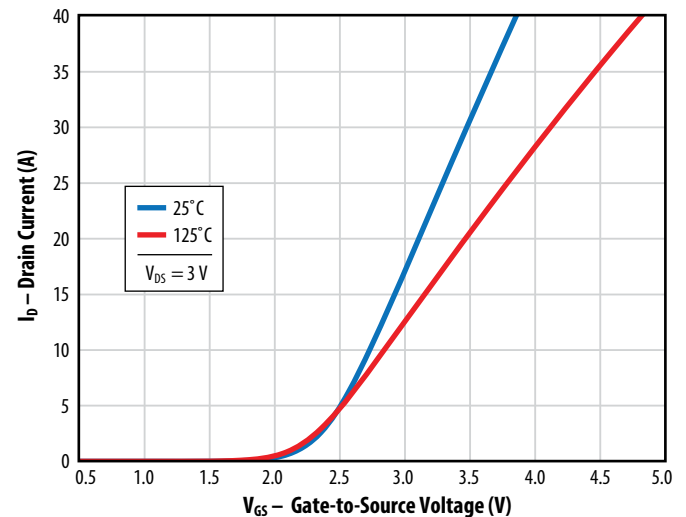
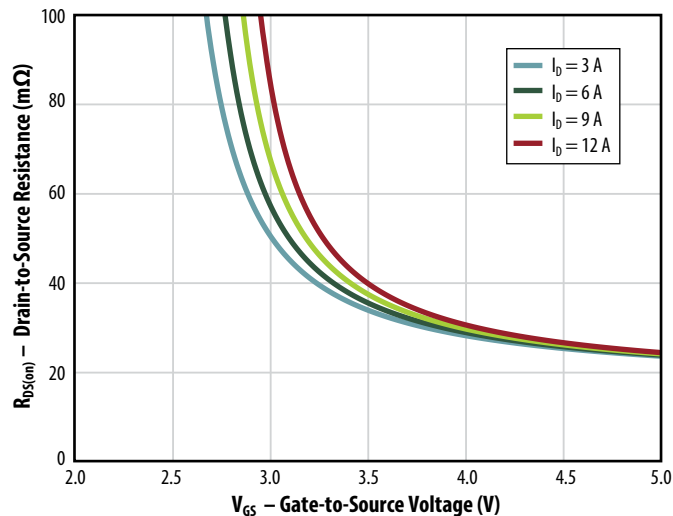
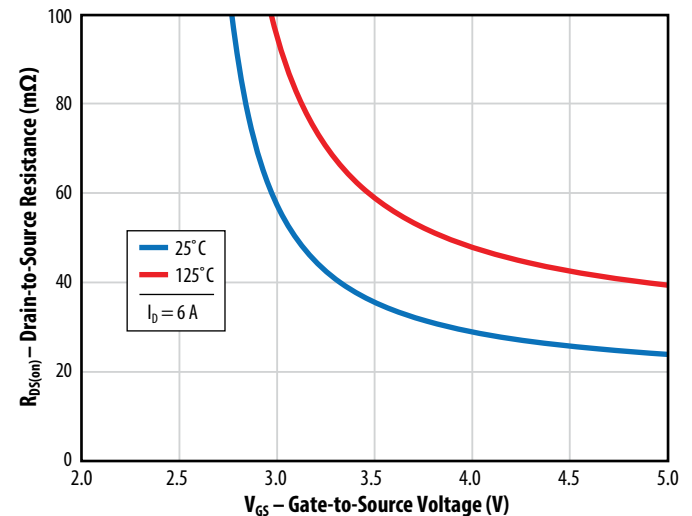
Figure 3: $R_{DS(on)}$ vs. V_{GS} for Various Drain CurrentsFigure 4: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

Figure 5a: Capacitance (Linear Scale)

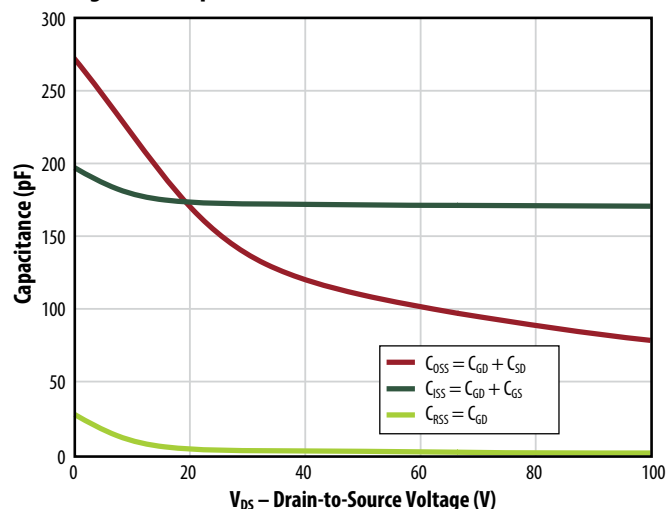


Figure 5b: Capacitance (Log Scale)

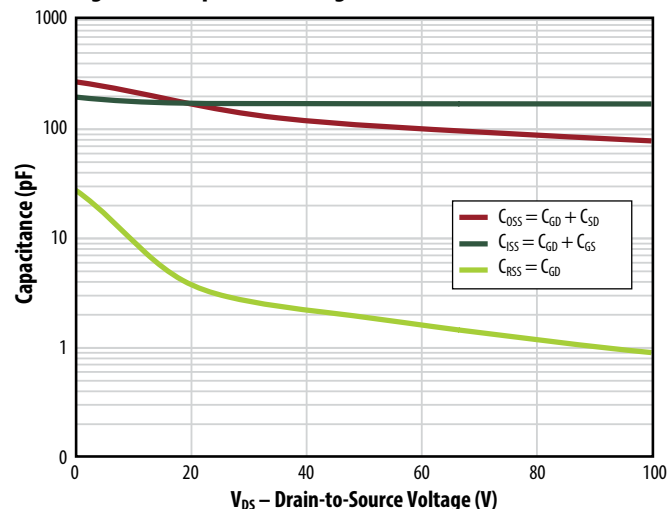


Figure 6: Gate Charge

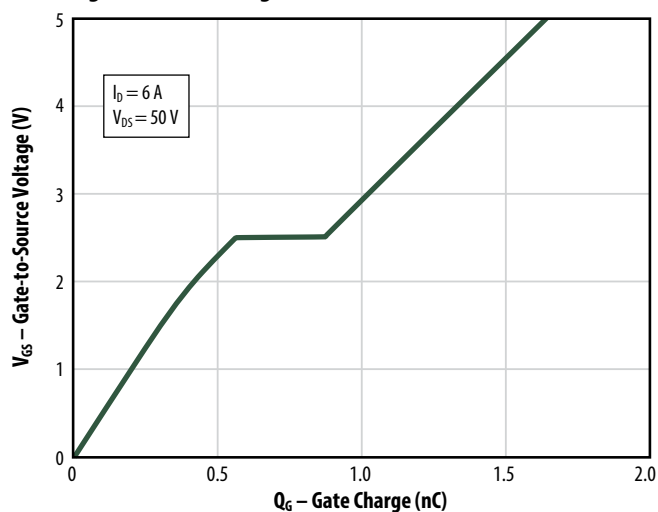


Figure 7: Reverse Drain-Source Characteristics

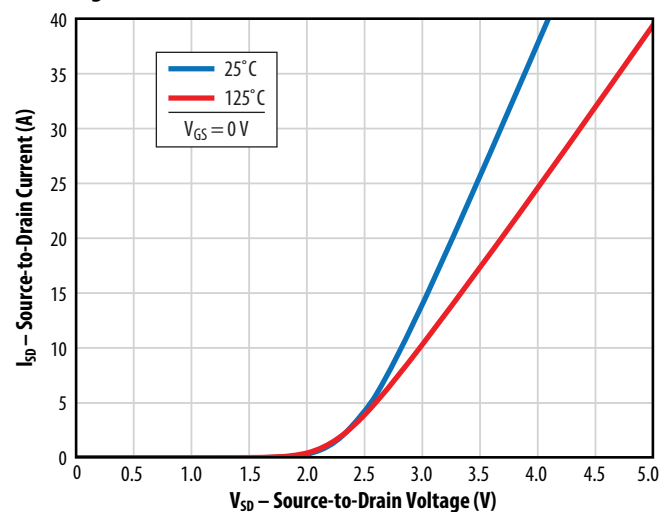


Figure 8: Normalized On-State Resistance vs. Temperature

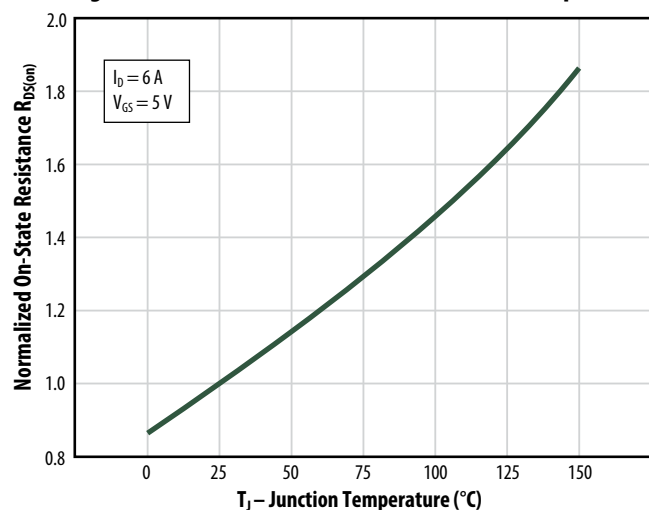
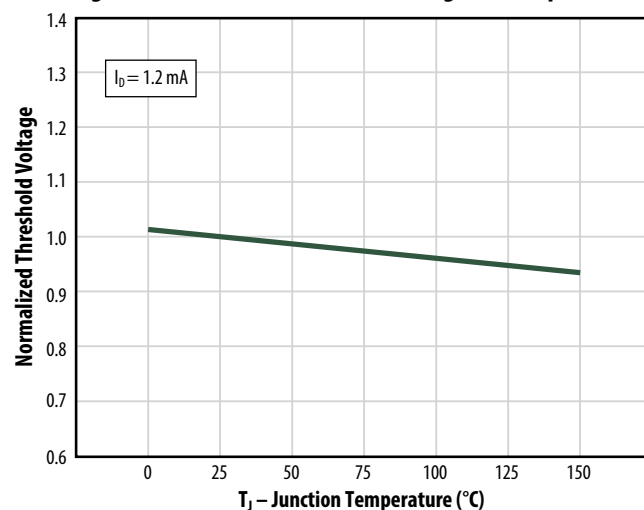


Figure 9: Normalized Threshold Voltage vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Gate Leakage Current

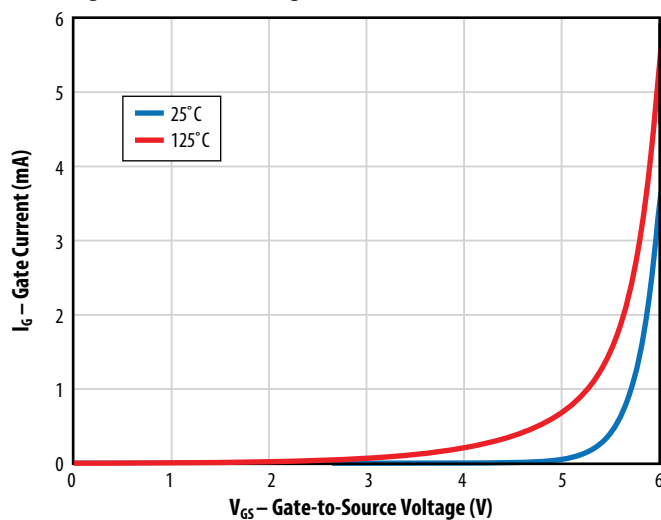


Figure 11: Transient Thermal Response Curves

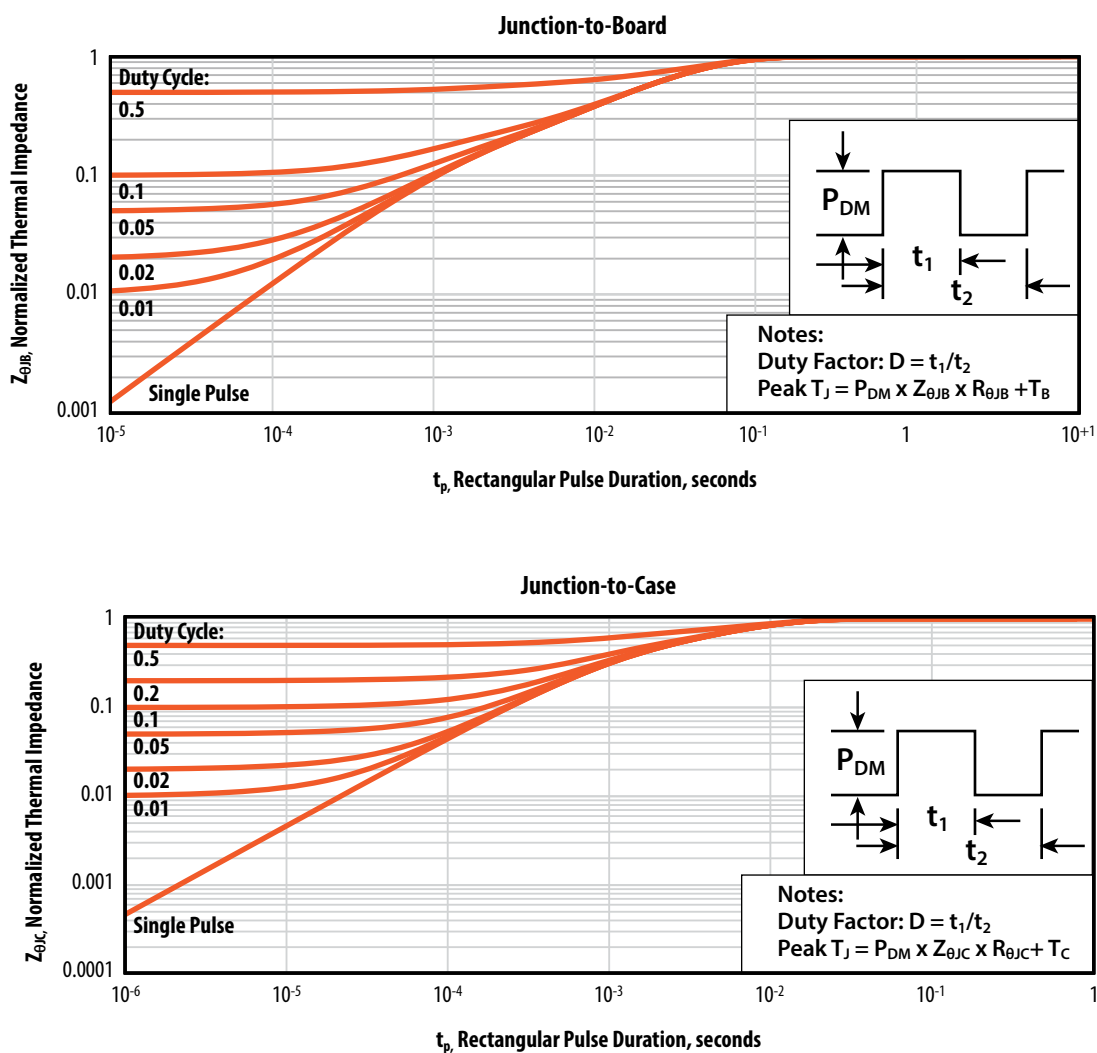
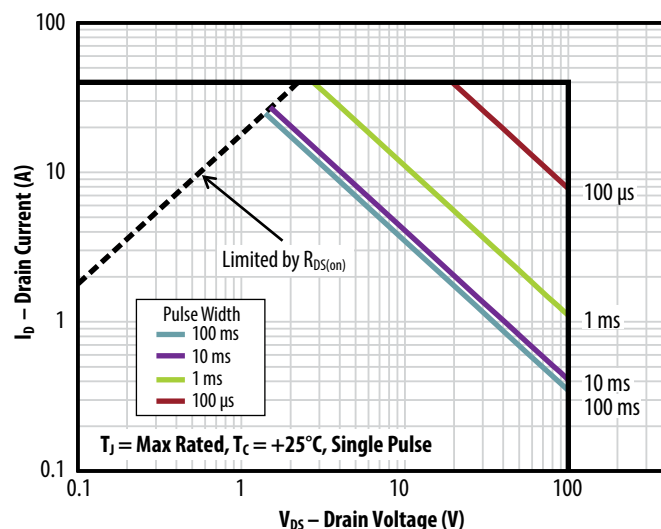
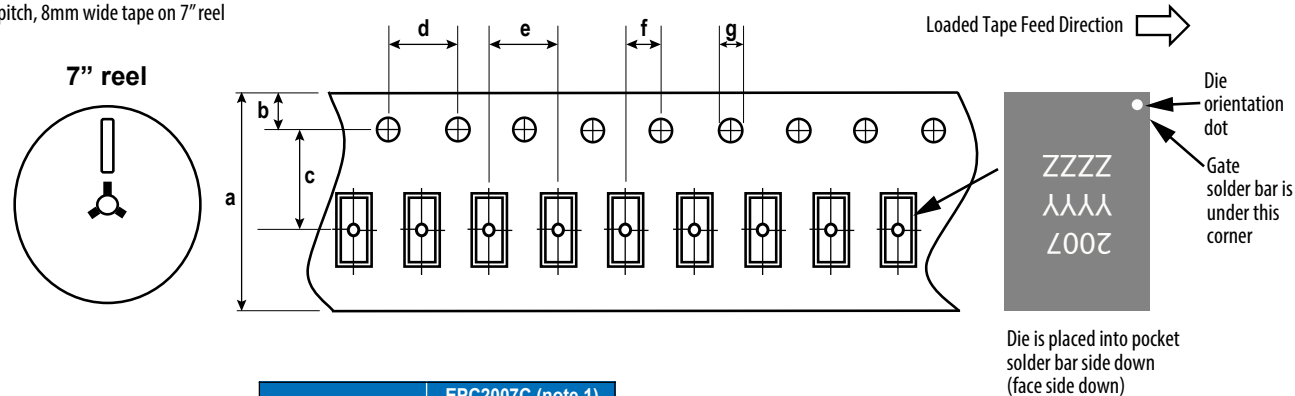


Figure 12: Safe Operating Area



TAPE AND REEL CONFIGURATION

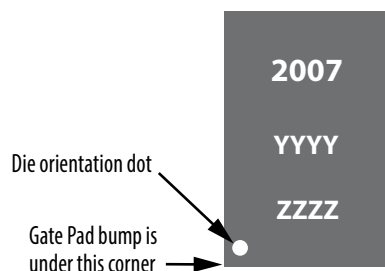
4mm pitch, 8mm wide tape on 7" reel



Dimension (mm)	EPC2007C (note 1)		
	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (note 2)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

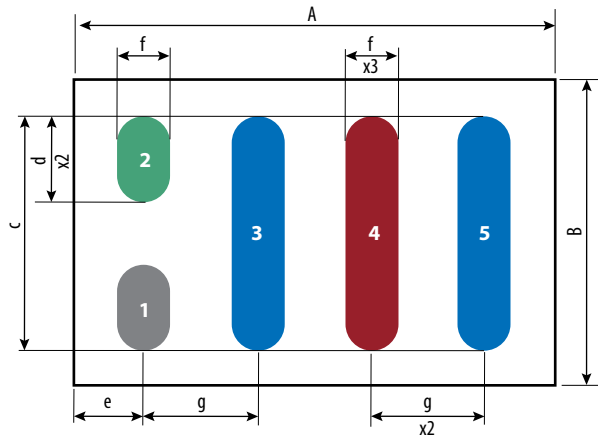
DIE MARKINGS



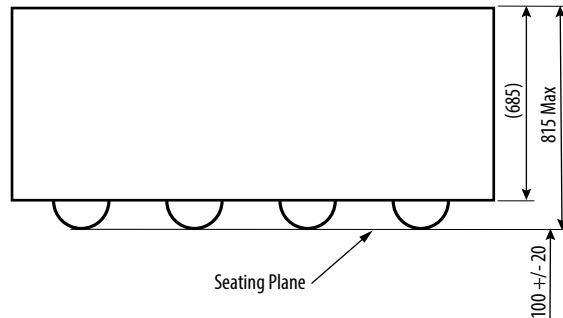
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
EPC2007C	2007	YYYY	ZZZZ

DIE OUTLINE

Solder Bar View



Side View



DIM	MICROMETERS		
	MIN	Nominal	MAX
A	1672	1702	1732
B	1057	1087	1117
C	829	834	839
D	311	316	321
E	235	250	265
F	195	200	205
G	400	400	400

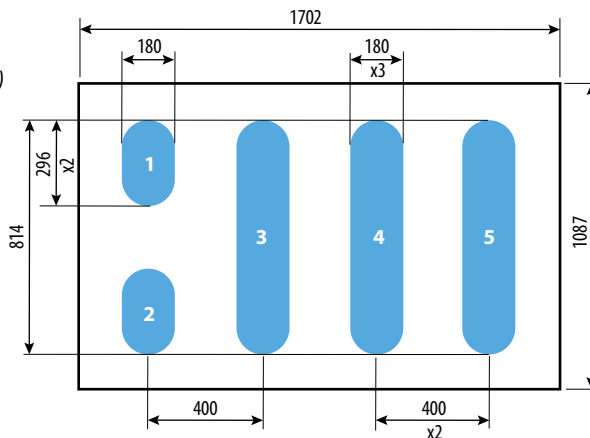
Pad no. 1 is Gate;

Pad no. 2 is Substrate,*

Pads no. 3 and 5 are Drain;

Pad no. 4 is Source

*Substrate pin should be connected to Source

RECOMMENDED LAND PATTERN(measurements in μm)The land pattern is solder mask defined
Solder mask is 10 μm smaller per side than bump

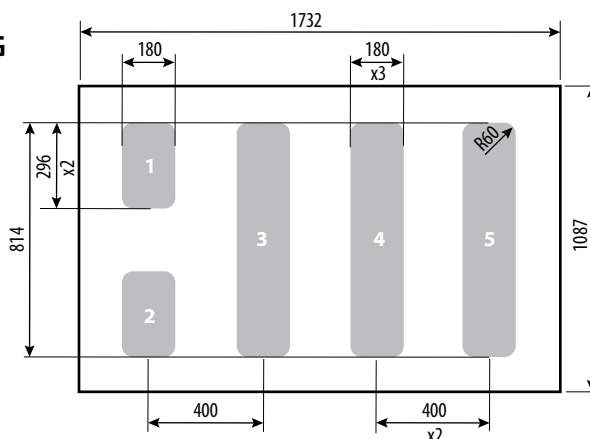
Pad no. 1 is Gate

Pad no. 2 is Substrate*

Pads no. 3 and 5 are Drain

Pad no. 4 is Source

*Substrate pin should be connected to Source

RECOMMENDED STENCIL DRAWING(units in μm)Recommended stencil should be 4 mil (100 μm)
thick, must be laser cut, opening per drawing.
The corner has a radius of R60.Intended for use with SAC305 Type 3 solder,
reference 88.5% metals content.Additional assembly resources available at
<https://www.epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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Revised April, 2021